



DOCUMENT CHANGE REQUEST

DCR number		1732	Changes required for:		N/A	Originator:		Khelifa Hadre	
Date:		2025/07/17	Date sent:		2025/03/28	Organisation:		ST Microelectronics	
Status:		IMPLEMENTED							
Title:		CMOS HEX Schmitt Triggers, based on type 40106B							
Number:		9409/005		Issue:		5			
Other documents affected:									
Page:									
14									
Paragraph:									
2.3.1 Room Temperature Electrical Measurements									
Original wording:									
Max Limit TPHL = 230 ns									
Proposed wording:									
Max Limit TPHL = 270 ns									
Justification:									
<p>During the radiation tests performed on recent diffusion lots at 100 krad Total dose on HCC40106B of the CMOS4000B family, the switching time performance exceeded the post radiation specification limit as defined in ST internal specification shared with customers in DEDICATED IRRADIATION TEST FLOW FOR CMOS TECHNOLOGY(0038618).</p> <p>The initial maximum limit pre radiation for TPHL (Propagation Delay High to Low) is 230 ns, and we propose a new limit of 270 ns to be able to pass 100krad radiation test with fresh diffusion lots preventing any product discontinuity.</p>									

Attachments:

N/A

Modifications:

N/A

Approval signature:



Date signed:

2025-07-17